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Trench gate field-stop IGBT, HB series 650 V, 30 A high speed

Datasheet - production data

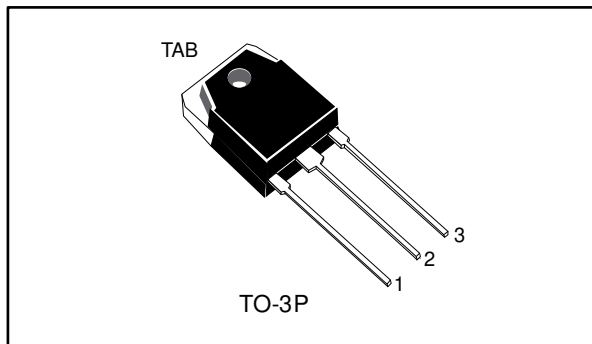
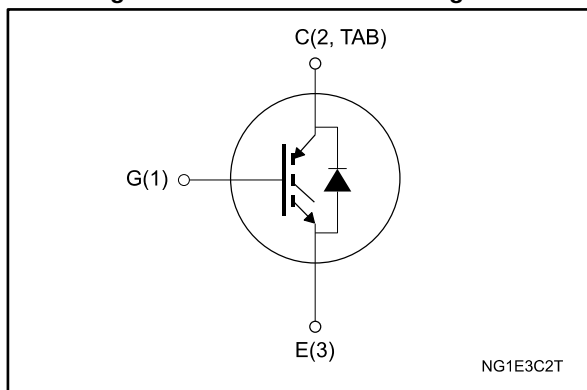


Figure 1: Internal schematic diagram



Features

- Maximum junction temperature: $T_J = 175\text{ }^{\circ}\text{C}$
- High speed switching series
- Minimized tail current
- $V_{CE(sat)} = 1.55\text{ V}$ (typ., $I_C = 30\text{ A}$)
- Safe paralleling
- Tight parameter distribution
- Low thermal resistance
- Co-packed diode for protection

Applications

- Power factor corrector (PFC)

Description

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the new HB series of IGBTs, which represents an optimum compromise between conduction and switching loss to maximize the efficiency of any frequency converter. Furthermore, the slightly positive $V_{CE(sat)}$ temperature coefficient and very tight parameter distribution result in safer paralleling operation.

Table 1: Device summary

Order code	Marking	Package	Packing
STGWT30HP65FB	GWT30HP65FB	TO-3P	Tube

Contents

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CES}	Collector-emitter voltage ($V_{GE} = 0$ V)	650	V
I_C	Continuous collector current at $T_C = 25$ °C	60	A
	Continuous collector current at $T_C = 100$ °C	30	
$I_{CP}^{(1)}$	Pulsed collector current	120	A
V_{GE}	Gate-emitter voltage	±20	V
$I_F^{(2)}$	Continuous forward current at $T_C = 25$ °C	5	A
	Continuous forward current at $T_C = 100$ °C	5	
$I_{FP}^{(3)}$	Pulsed forward current	10	A
P_{TOT}	Total dissipation at $T_C = 25$ °C	260	W
T_{STG}	Storage temperature range	-55 to 150	°C
T_J	Operating junction temperature range	-55 to 175	

Notes:

(1) Pulse width limited by maximum junction temperature

(2) Limited by wires

(3) Pulsed forward current

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance junction-case IGBT	0.58	°C/W
R_{thJC}	Thermal resistance junction-case diode	5	
R_{thJA}	Thermal resistance junction-ambient	50	

2 Electrical characteristics

$T_J = 25\text{ °C}$ unless otherwise specified

Table 4: Static characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage	$V_{GE} = 0\text{ V}$, $I_C = 2\text{ mA}$	650			V
$V_{CE(sat)}$	Collector-emitter saturation voltage	$V_{GE} = 15\text{ V}$, $I_C = 30\text{ A}$		1.55	2.0	V
		$V_{GE} = 15\text{ V}$, $I_C = 30\text{ A}$, $T_J = 125\text{ °C}$		1.65		
		$V_{GE} = 15\text{ V}$, $I_C = 30\text{ A}$, $T_J = 175\text{ °C}$		1.75		
V_F	Forward on-voltage	$I_F = 5\text{ A}$		2.0		V
		$I_F = 5\text{ A}$, $T_J = 125\text{ °C}$		1.85		
		$I_F = 5\text{ A}$, $T_J = 175\text{ °C}$		1.75		
$V_{GE(th)}$	Gate threshold voltage	$V_{CE} = V_{GE}$, $I_C = 1\text{ mA}$	5	6	7	V
I_{CES}	Collector cut-off current	$V_{GE} = 0\text{ V}$, $V_{CE} = 650\text{ V}$			25	μA
I_{GES}	Gate-emitter leakage current	$V_{CE} = 0\text{ V}$, $V_{GE} = \pm 20\text{ V}$			± 250	nA

Table 5: Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{ies}	Input capacitance	$V_{CE} = 25\text{ V}$, $f = 1\text{ MHz}$, $V_{GE} = 0\text{ V}$	-	3659	-	pF
C_{oes}	Output capacitance		-	101	-	
C_{res}	Reverse transfer capacitance		-	76	-	
Q_g	Total gate charge	$V_{CC} = 520\text{ V}$, $I_C = 30\text{ A}$, $V_{GE} = 15\text{ V}$ (see Figure 28: "Gate charge test circuit")	-	149	-	nC
Q_{ge}	Gate-emitter charge		-	25	-	
Q_{gc}	Gate-collector charge		-	62	-	

Table 6: IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$	Turn-off-delay time	$V_{CE} = 400\text{ V}$, $I_C = 30\text{ A}$, $V_{GE} = 15\text{ V}$, $R_G = 10\text{ }\Omega$ (see Figure 27: "Test circuit for inductive load switching")	-	146	-	ns
t_f	Current fall time		-	23	-	ns
$E_{off(1)}$	Turn-off switching energy		-	293	-	μJ
$t_{d(off)}$	Turn-off-delay time	$V_{CE} = 400\text{ V}$, $I_C = 30\text{ A}$, $V_{GE} = 15\text{ V}$, $R_G = 10\text{ }\Omega$, $T_J = 175\text{ °C}$ (see Figure 27: "Test circuit for inductive load switching")	-	158	-	ns
t_f	Current fall time		-	65	-	ns
E_{off}	Turn-off switching energy		-	572	-	μJ

Notes:

⁽¹⁾Including the tail of the collector current.

Table 7: Diode switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
t_{rr}	Reverse recovery time	$I_F = 5\text{ A}$, $V_R = 400\text{ V}$, $V_{GE} = 15\text{ V}$, $di/dt = 1000\text{ A}/\mu\text{s}$ (see Figure 27: "Test circuit for inductive load switching")	-	140	-	ns
Q_{rr}	Reverse recovery charge		-	21	-	nC
I_{rrm}	Reverse recovery current		-	6.6	-	A
dl_{rr}/dt	Peak rate of fall of reverse recovery current during t_b		-	430	-	A/ μs
E_{rr}	Reverse recovery energy		-	1.6	-	μJ
t_{rr}	Reverse recovery time	$I_F = 5\text{ A}$, $V_R = 400\text{ V}$, $V_{GE} = 15\text{ V}$ $T_J = 175\text{ }^\circ\text{C}$, $di/dt = 1000\text{ A}/\mu\text{s}$ (see Figure 27: "Test circuit for inductive load switching")	-	200	-	ns
Q_{rr}	Reverse recovery charge		-	47.3	-	nC
I_{rrm}	Reverse recovery current		-	9.6	-	A
dl_{rr}/dt	Peak rate of fall of reverse recovery current during t_b		-	428	-	A/ μs
E_{rr}	Reverse recovery energy		-	3.2	-	μJ

2.1 Electrical characteristics (curves)

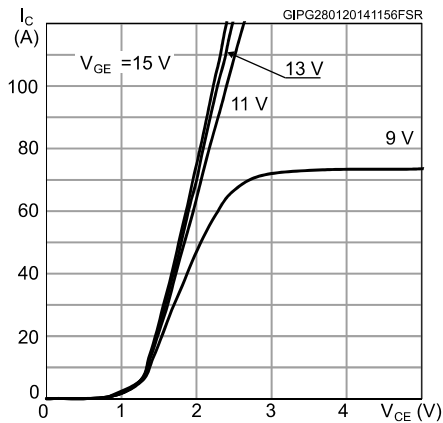
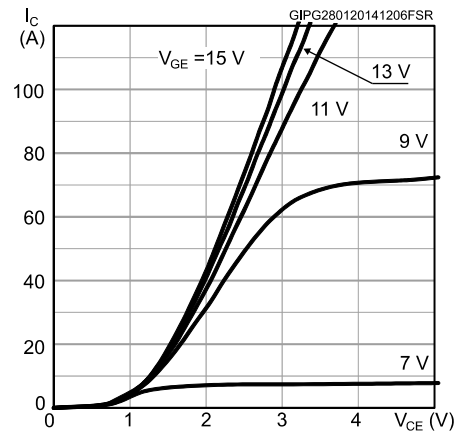
Figure 2: Output characteristics ($T_J = 25^\circ\text{C}$)Figure 3: Output characteristics ($T_J = 175^\circ\text{C}$)

Figure 4: Transfer characteristics

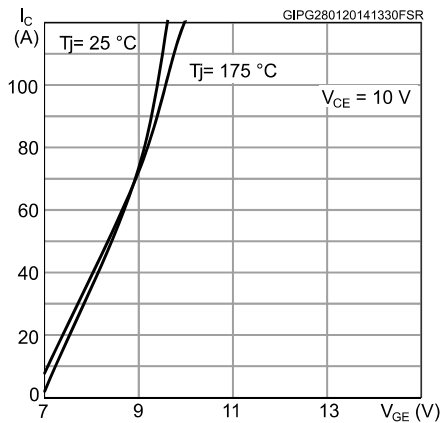


Figure 5: Collector current vs. case temperature for TO-3P

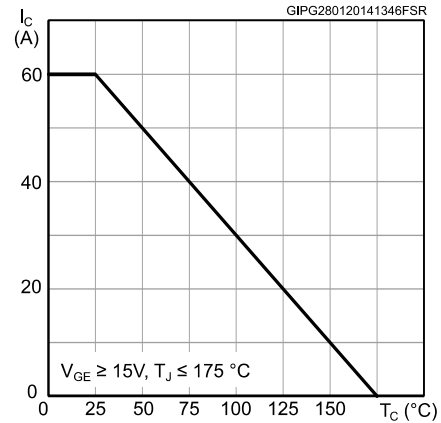
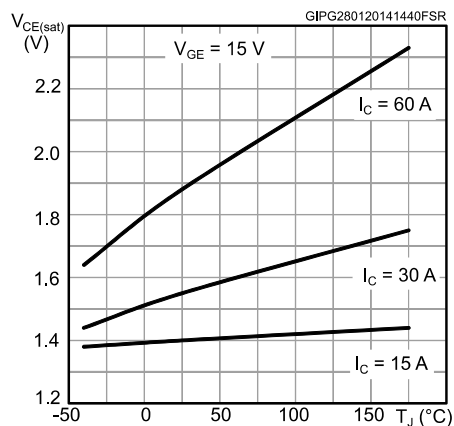
Figure 6: $V_{CE(sat)}$ vs. junction temperature

Figure 7: Power dissipation vs. case temperature for TO-3P

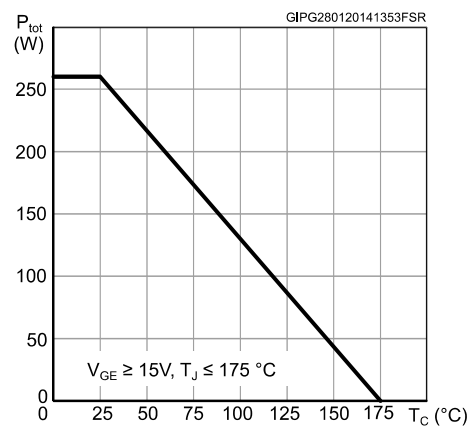


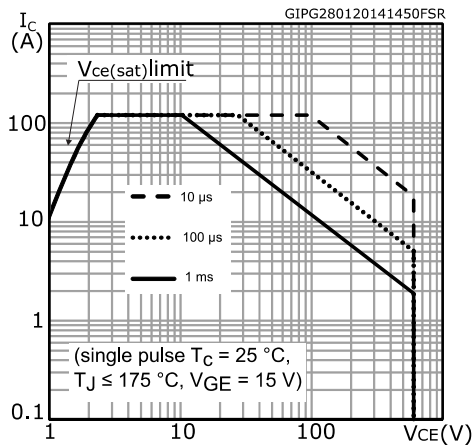
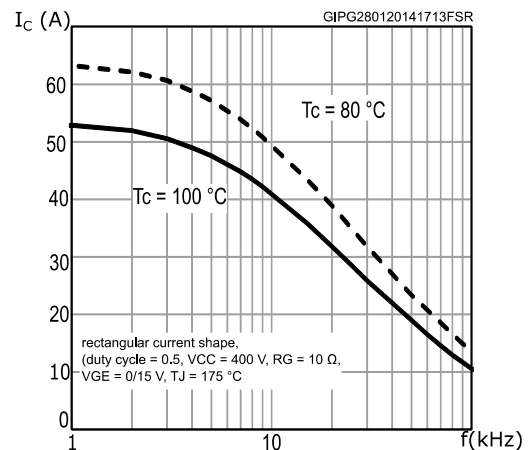
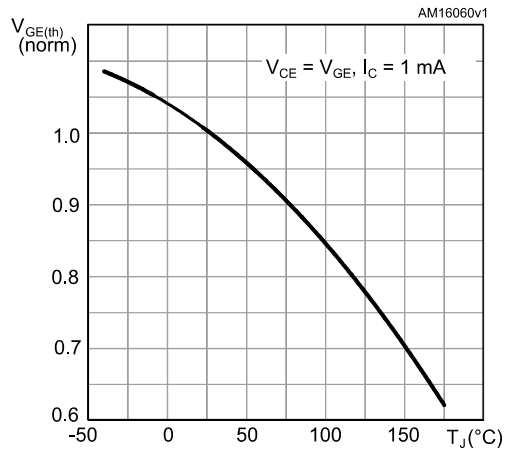
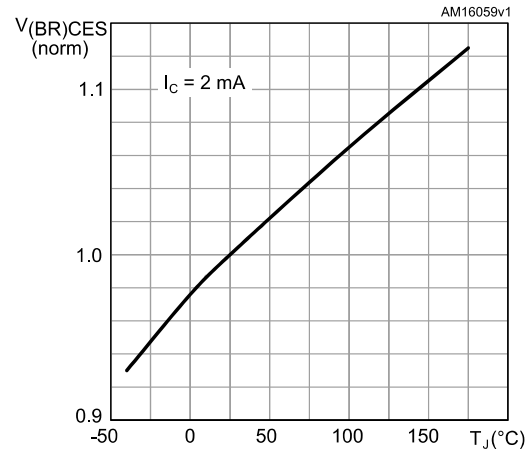
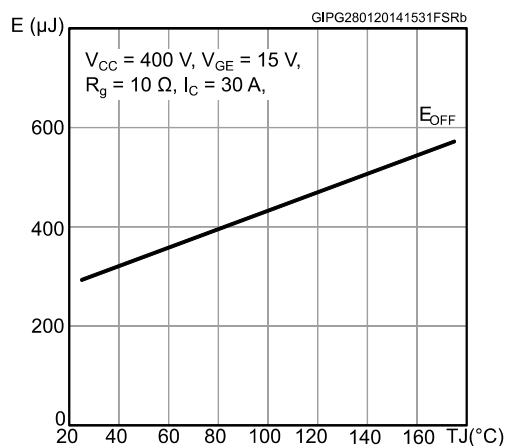
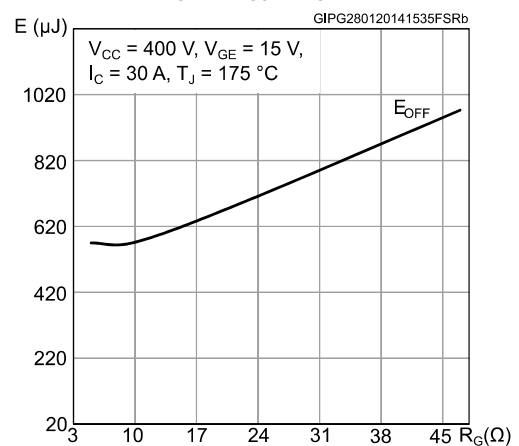
Figure 8: Forward bias safe operating area for TO-3P**Figure 9: Collector current vs. switching frequency for TO-3P****Figure 10: Normalized $V_{GE(th)}$ vs. junction temperature****Figure 11: Normalized $V_{(BR)CES}$ vs. junction temperature****Figure 12: Switching energy vs temperature****Figure 13: Switching energy vs gate resistance**

Figure 14: Switching energy vs collector current

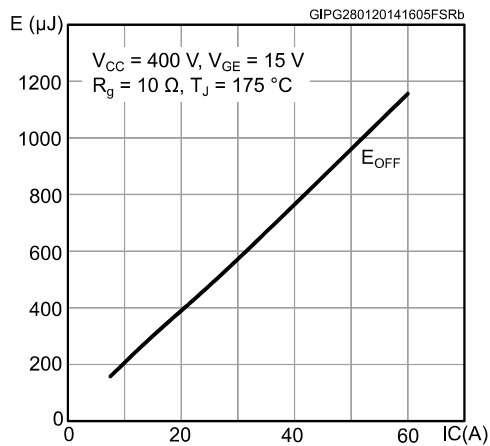


Figure 15: Switching energy vs collector emitter voltage

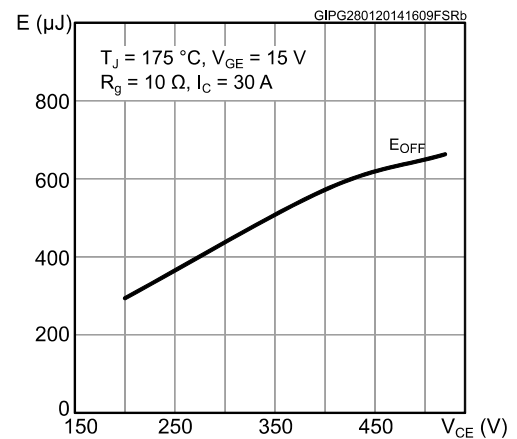


Figure 16: Switching times vs collector current

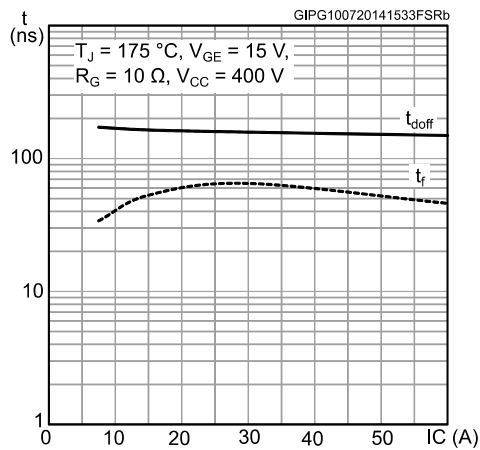


Figure 17: Switching times vs gate resistance

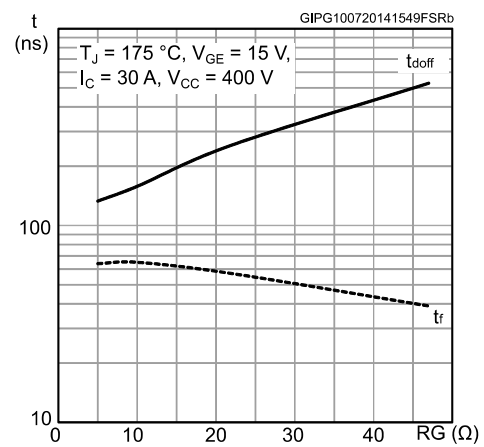


Figure 18: Capacitance variations

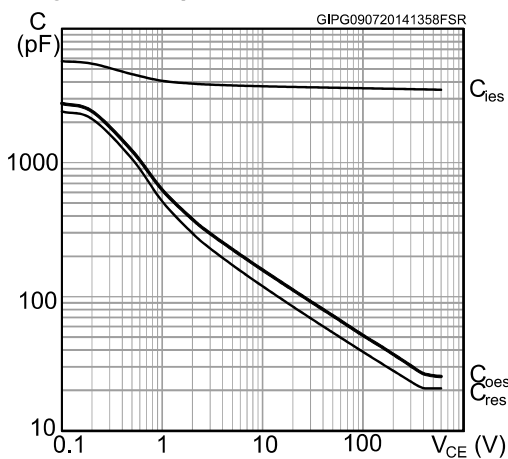
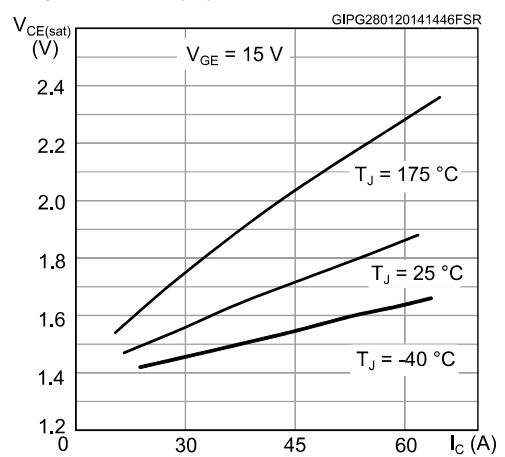
Figure 19: $V_{CE(sat)}$ vs. collector current

Figure 20: Gate charge vs. gate-emitter voltage

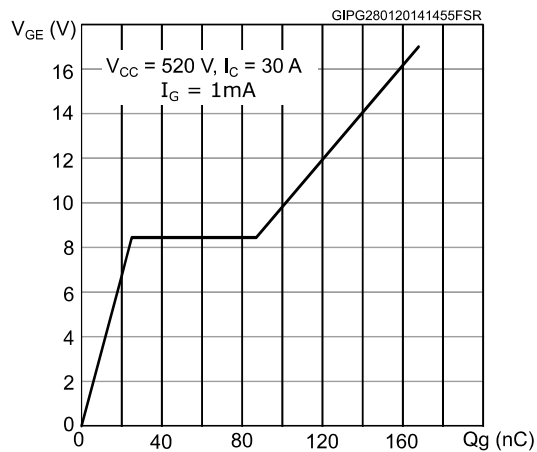
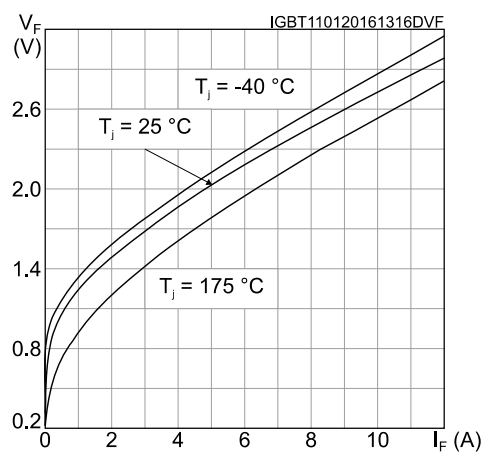
Figure 21: Diode V_F vs. forward current

Figure 22: Reverse recovery current vs. diode current slope

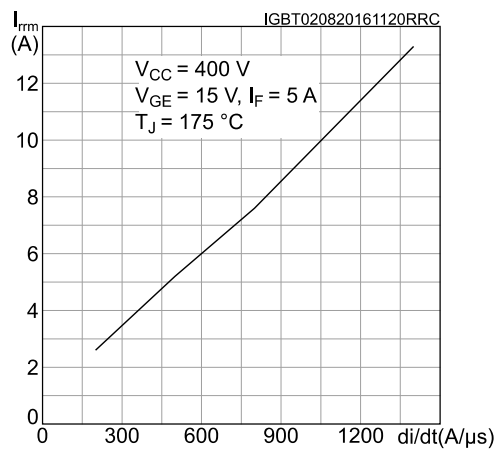


Figure 23: Reverse recovery time vs. diode current slope

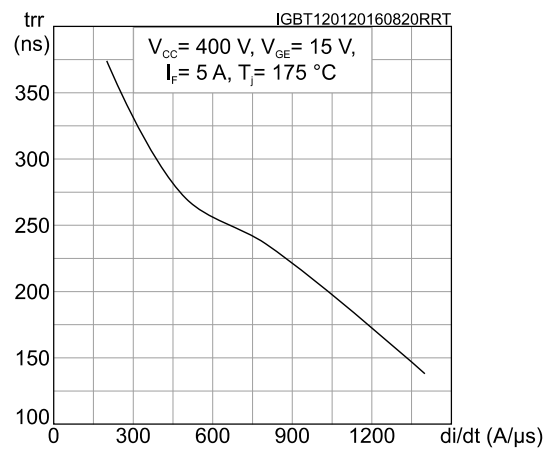


Figure 24: Reverse recovery charge vs. diode current slope

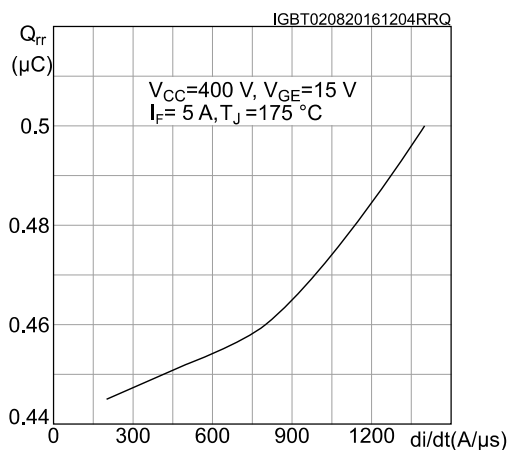


Figure 25: Reverse recovery energy vs. diode current slope

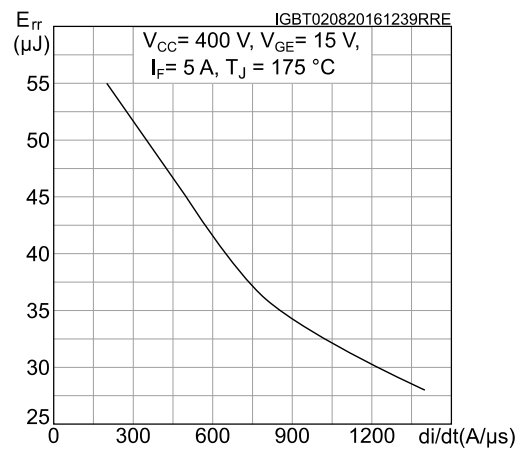
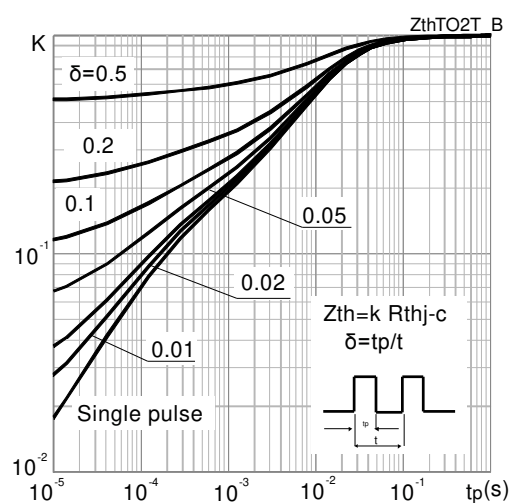
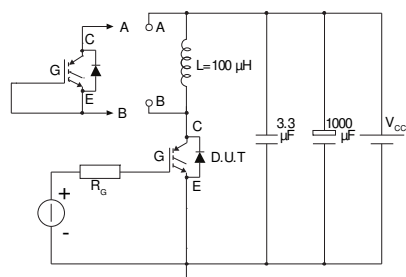


Figure 26: Thermal impedance for IGBT



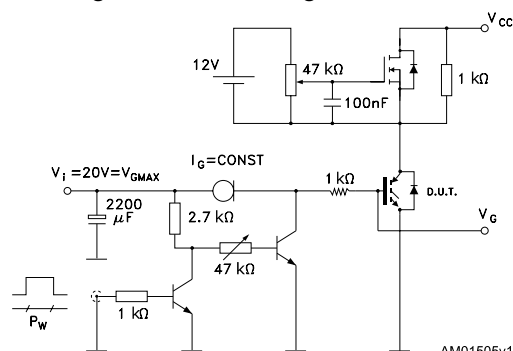
3 Test circuits

Figure 27: Test circuit for inductive load switching



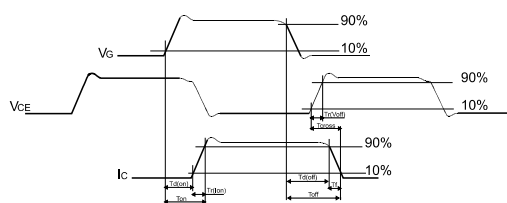
AM01504v1

Figure 28: Gate charge test circuit



AM01505v1

Figure 29: Switching waveform



AM01506v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 TO-3P package information

Figure 30: TO-3P package outline

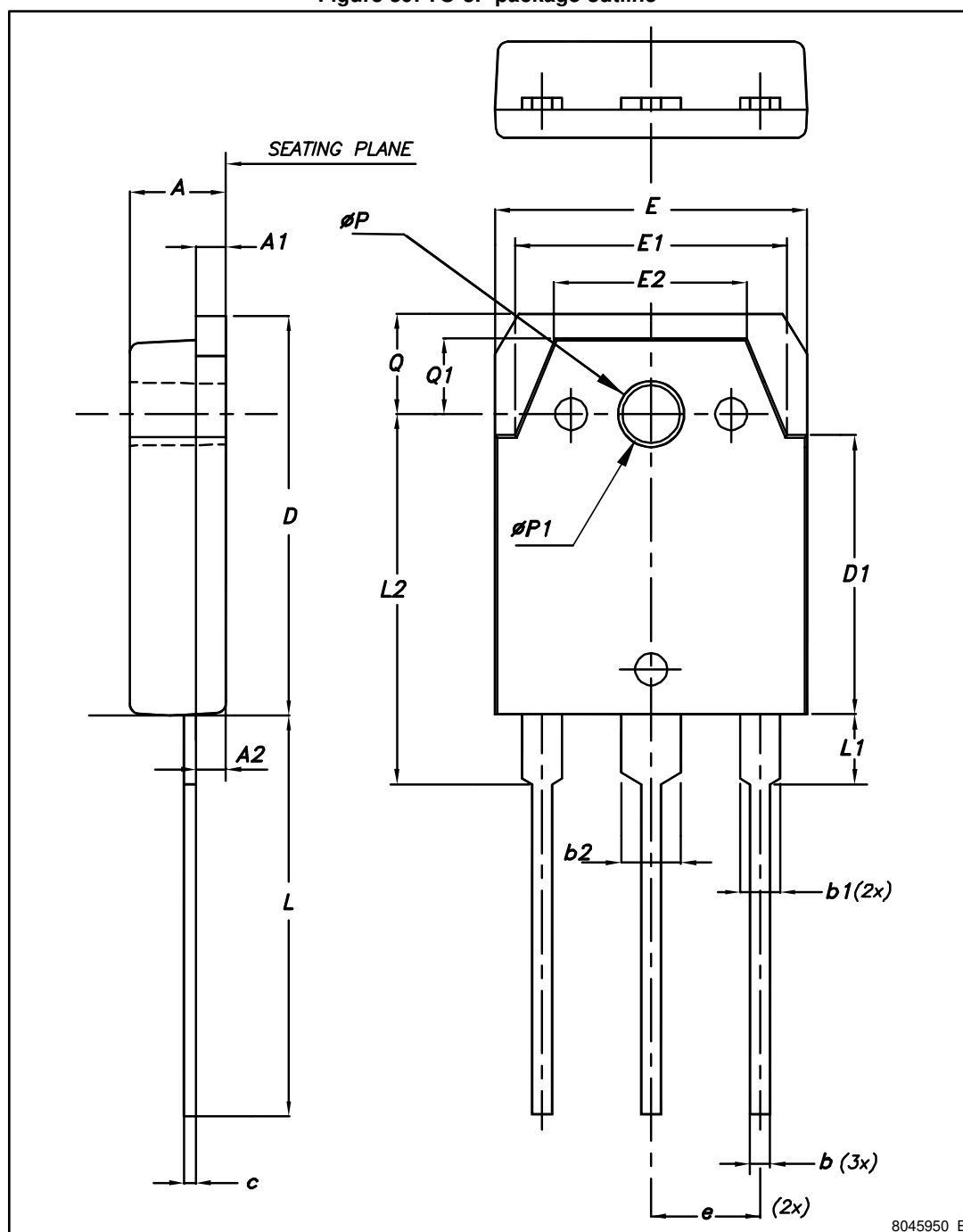


Table 8: TO-3P package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.60	4.80	5.00
A1	1.45	1.50	1.65
A2	1.20	1.40	1.60
b	0.80	1.00	1.20
b1	1.80	2.00	2.20
b2	2.80	3.00	3.20
c	0.55	0.60	0.75
D	19.70	19.90	20.10
D1	13.70	13.90	14.10
E	15.40	15.60	15.80
E1	13.40	13.60	13.80
E2	9.40	9.60	9.90
e	5.15	5.45	5.75
L	19.80	20.00	20.20
L1	3.30	3.50	3.70
L2	18.20	18.40	18.60
ØP	3.30	3.40	3.50
ØP1	3.10	3.20	3.30
Q	4.80	5.00	5.20
Q1	3.60	3.80	4

5 Revision history

Table 9: Document revision history

Date	Revision	Changes
11-Nov-2015	1	First release
20-Jan-2017	2	Datasheet status promoted from preliminary to production data. Updated Features on cover page. Updated Section 1: "Electrical ratings" and Section 2: "Electrical characteristics" . Minor text changes

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